

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant	: Hideaki Kuwabara et al.	Art Unit	: 2822
Serial No.	: 10/735,767	Examiner	: Kevin Picardat
Filed	: December 16, 2003	Conf. No.	: 4086
Title	: SEMICONDUCTOR DEVICE AND METHOD FOR MANUFACTURING THE SAME		

MAIL STOP AF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This information disclosure statement is being filed concurrently with a Request for Continued Examination. The fee in the amount of \$790.00 in payment of the Request for Continued Examination fee is being paid concurrently herewith on the Electronic Filing System (EFS) by way of Deposit Account authorization. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: January 4, 2007



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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-189001	Application No. 10/735,767
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Hideaki Kuwabara et al.	
		Filing Date December 16, 2003	Group Art Unit 2822

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2002/0055237	05/09/2002	Sayyah			09/12/2001
	AB	6,027,958	02/22/2000	Vu et al.			07/11/1996
	AC	6,143,582	11/07/2000	Vu et al.			02/12/1999
	AD	2002/0016028	02/07/2002	Arao et al.			06/05/2001
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	